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DETERMINATION OF ACTIVATION ENERGY IN TEXTURED METAL-METAL MULTILAYER FILMS VIA 2D XRD

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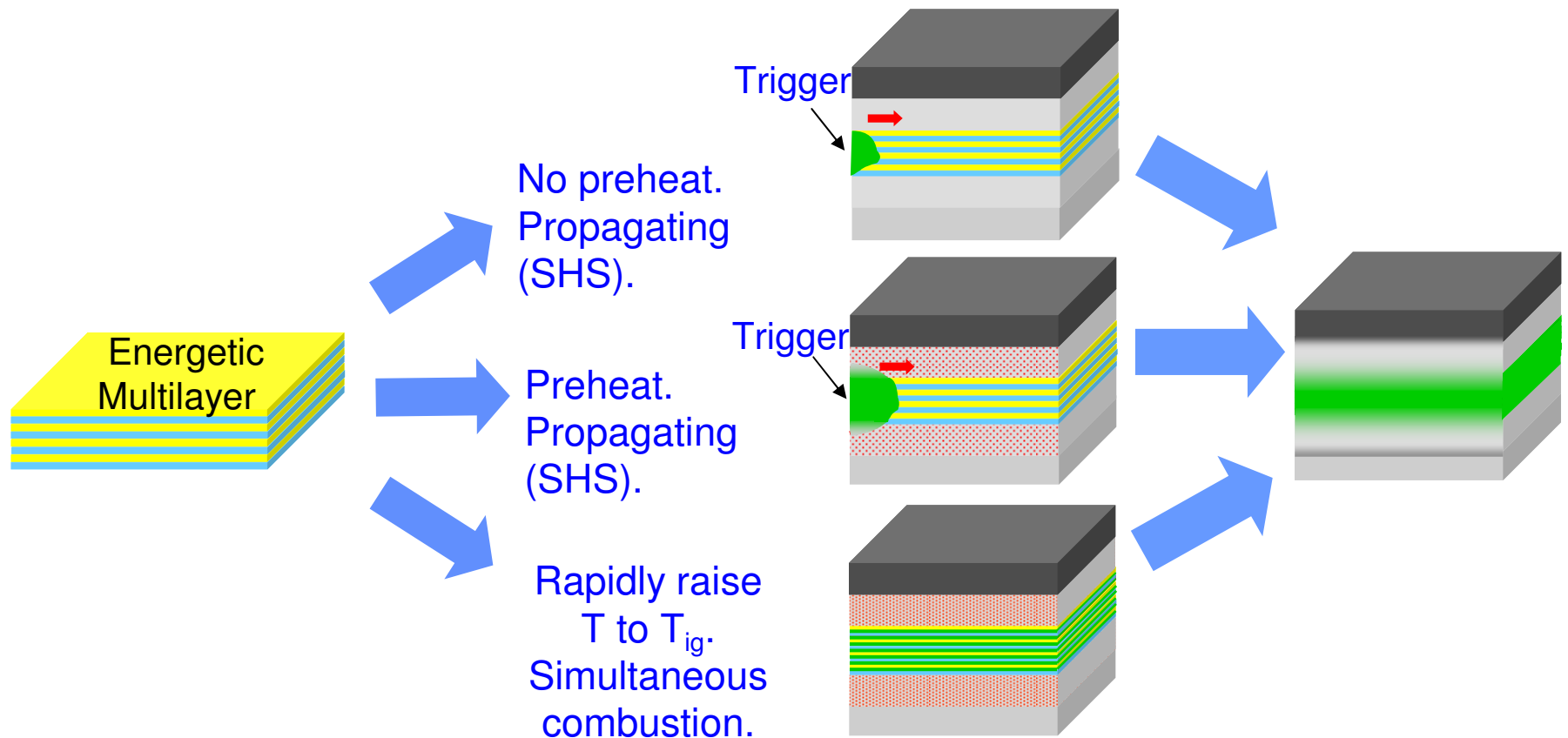
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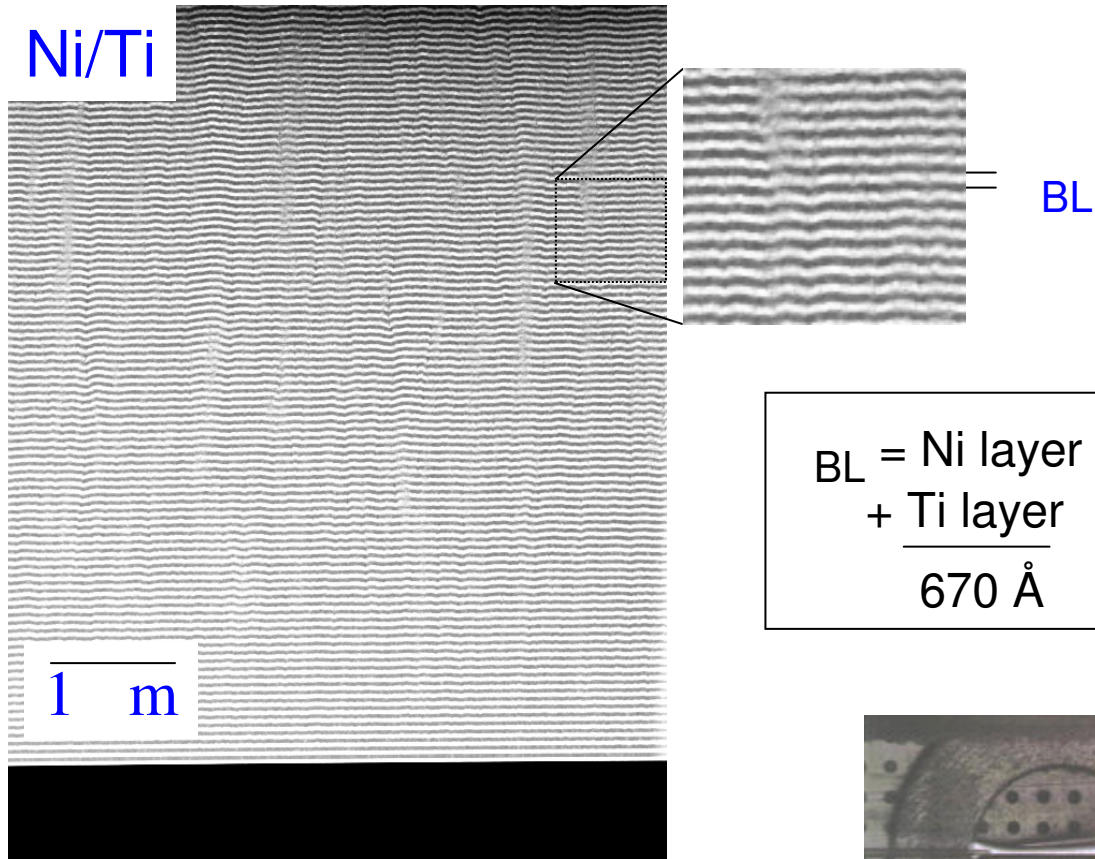


Metal-Metal thin film multilayers store significant energy which can be employed for materials joining

SHS = Self-propagating High-temperature Synthesis
- combustion synthesis

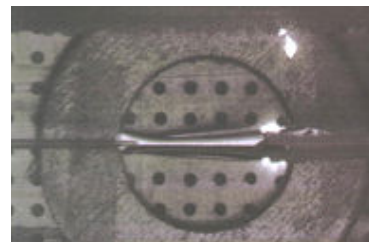


Exothermic thin-film multilayers are heterostructures that consist of two or more species that react.



Typical design:

- Large negative H_f
- Can exhibit high-T combustion synthesis (self-propagating)



NiTi



AlPt

¹ J.A. Floro, J. Vac. Sci. Technol. A, 1986.

² L.A. Clevenger, C.V. Thompson and K.N. Tu, J. App. Phys. 1990.

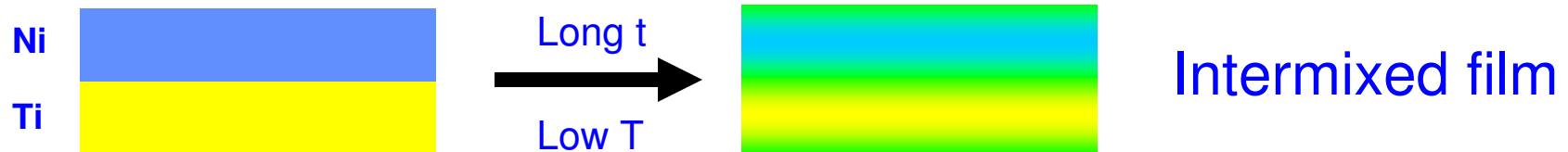
³ T.W. Barbee, T. Weihs, US Patents 5,538,795 5,547,715, 1995.

⁴ C. Suryanarayana, J.J. Moore, R. Radtke, Adv. Mat. and Proc. (2001).



We desired to evaluate not the fast Rx during SHS, but the slower “intermixing” Rx for shelf-life prediction

Slow diffusion of reactants at relatively low temperature (T) over a long time (t) could significantly reduce the stored energy for SHS



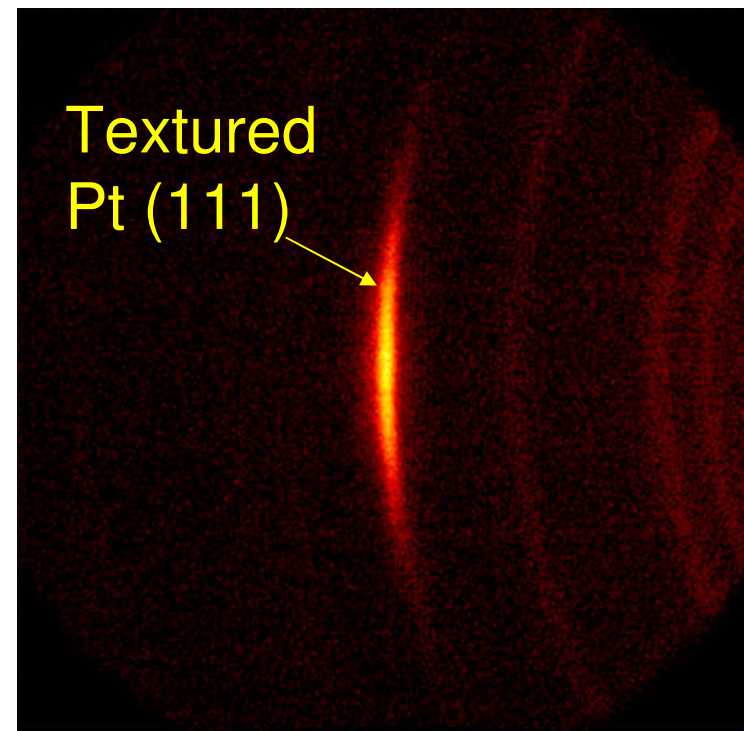
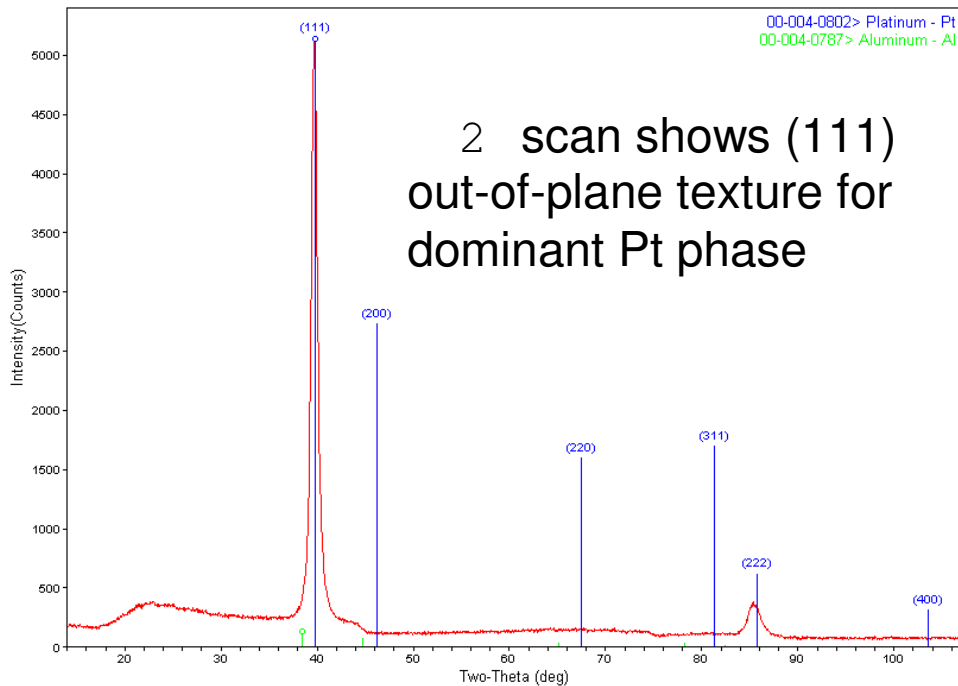
Our approach:

- monitor one film constituent as a $f_n(t)$ at various temperature values.
- assume pseudo-first-order behavior for Rx.
- determine rate constants for decay of Intensity of reactant as $F_n(T)$.
- calculate activation energy for intermixing Rx by Arrhenius relationship.

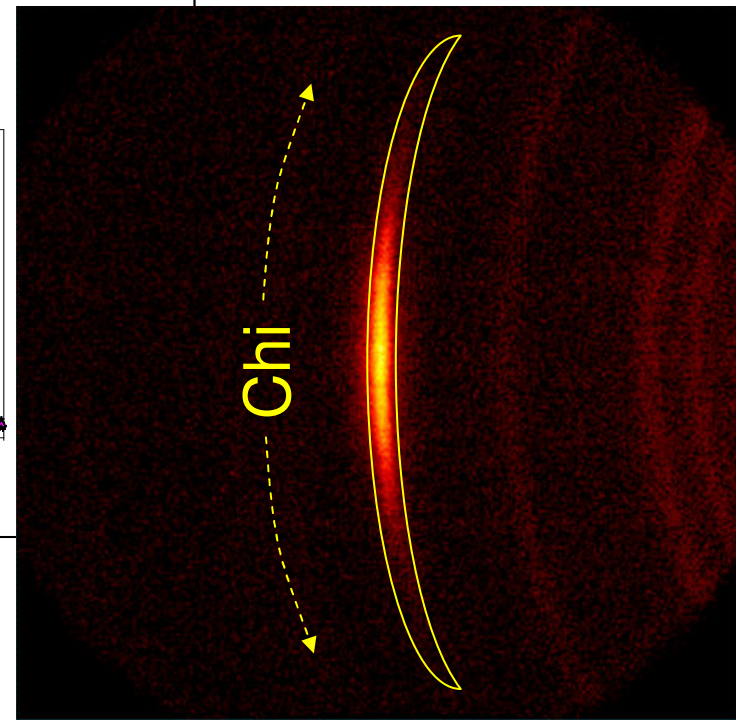
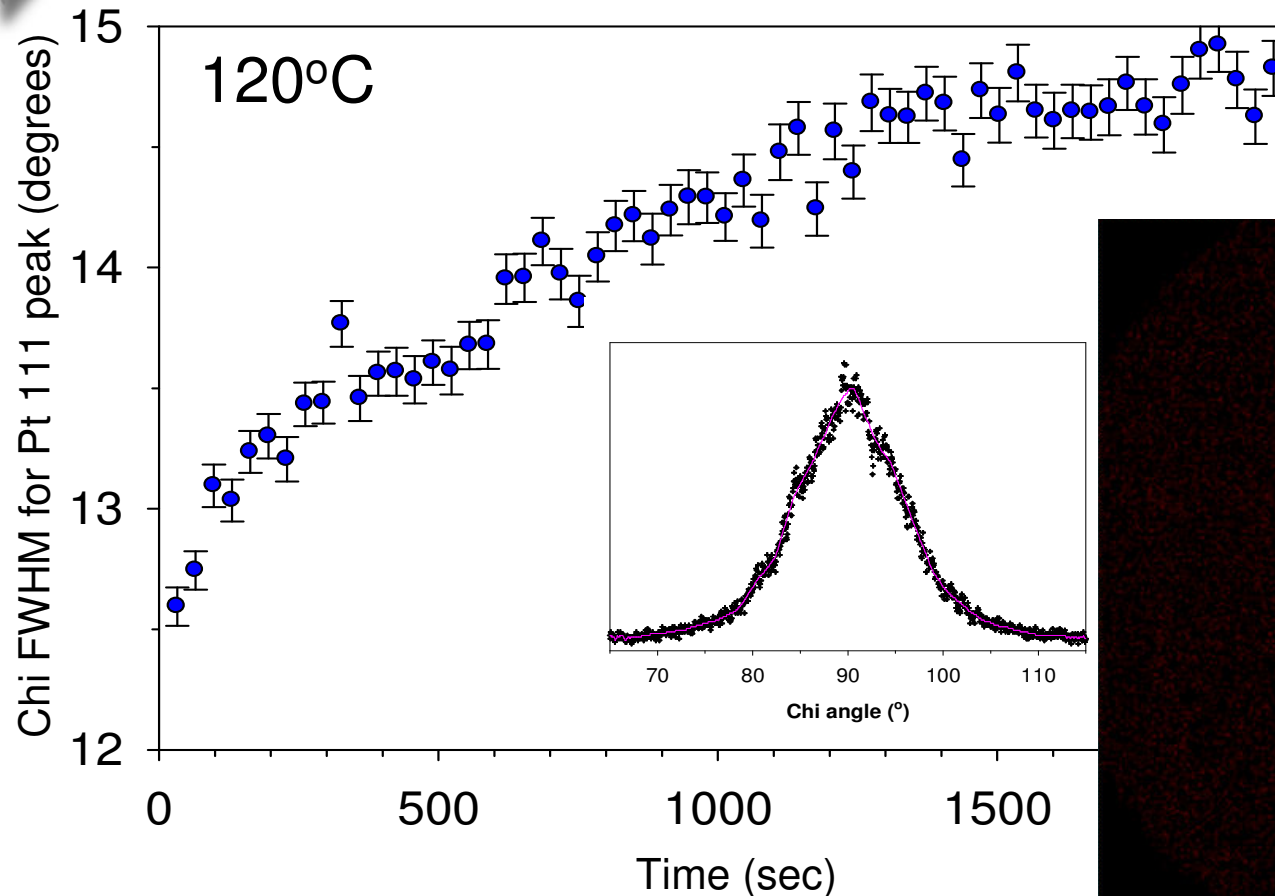


Problem: Multilayer films are often textured. What if texture decreases as sample reacts?

If we measure standard θ scans we could be assigning intensity loss from peak assuming loss of constituent concentration and not decay of texture.



Integration along Chi indicates Pt (111) peak
FWHM is increasing during intermixing Rx



To account for change in texture during Rx we
integrate intensity as a window of 2° and Chi

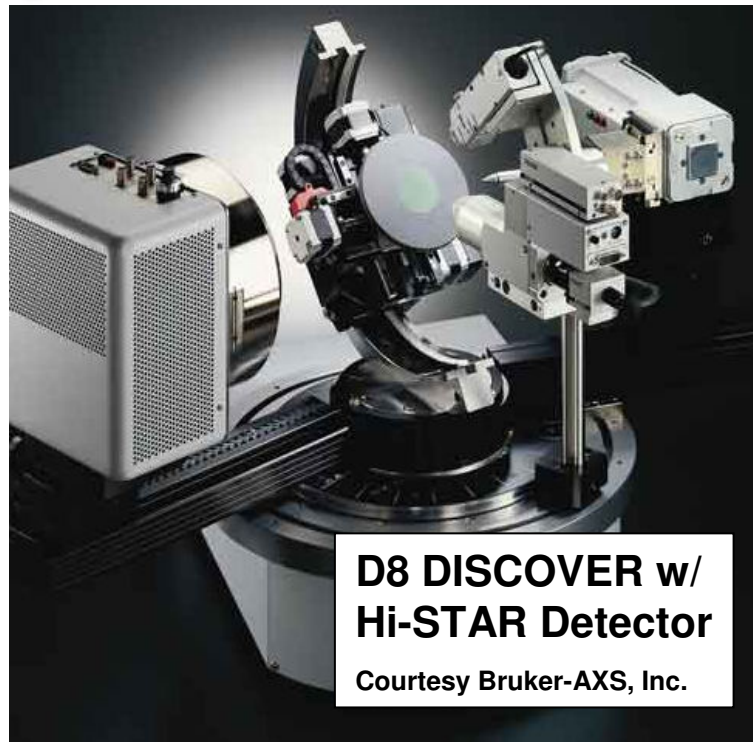


Metal-Metal multilayer films were made using an in-house sputter system.

- Films were deposited by direct-current sputtering
 - cryopumped vacuum system (Unifilm, Boulder CO)
 - base pressure = 8×10^{-8} Torr
 - Argon sputtering gas (10 mTorr)
- high purity elemental targets employed
 - Al (99.995%), Pt (99.95%)
 - Ni (99.99%), Ti (99.99%)
 - Co (99.99%), Al (99.995%)
- Deposited on 0.5mm thick fused Silica substrates
 - Substrate temperature $< 50^{\circ}\text{C}$

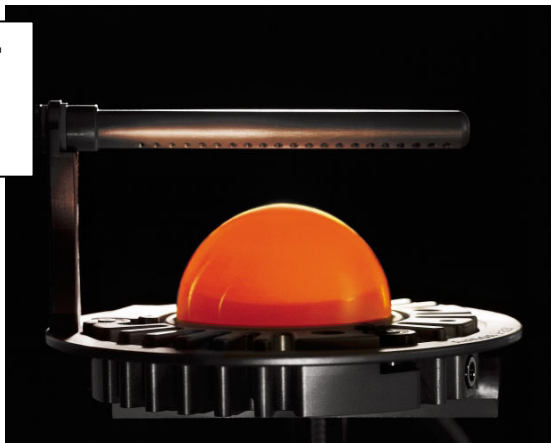


Data collection employed a Bruker D8 system equipped with a Anton-Paar stage



**Anton-Paar
DHS 900
hot stage**

*Courtesy
Anton-Paar
GmbH*

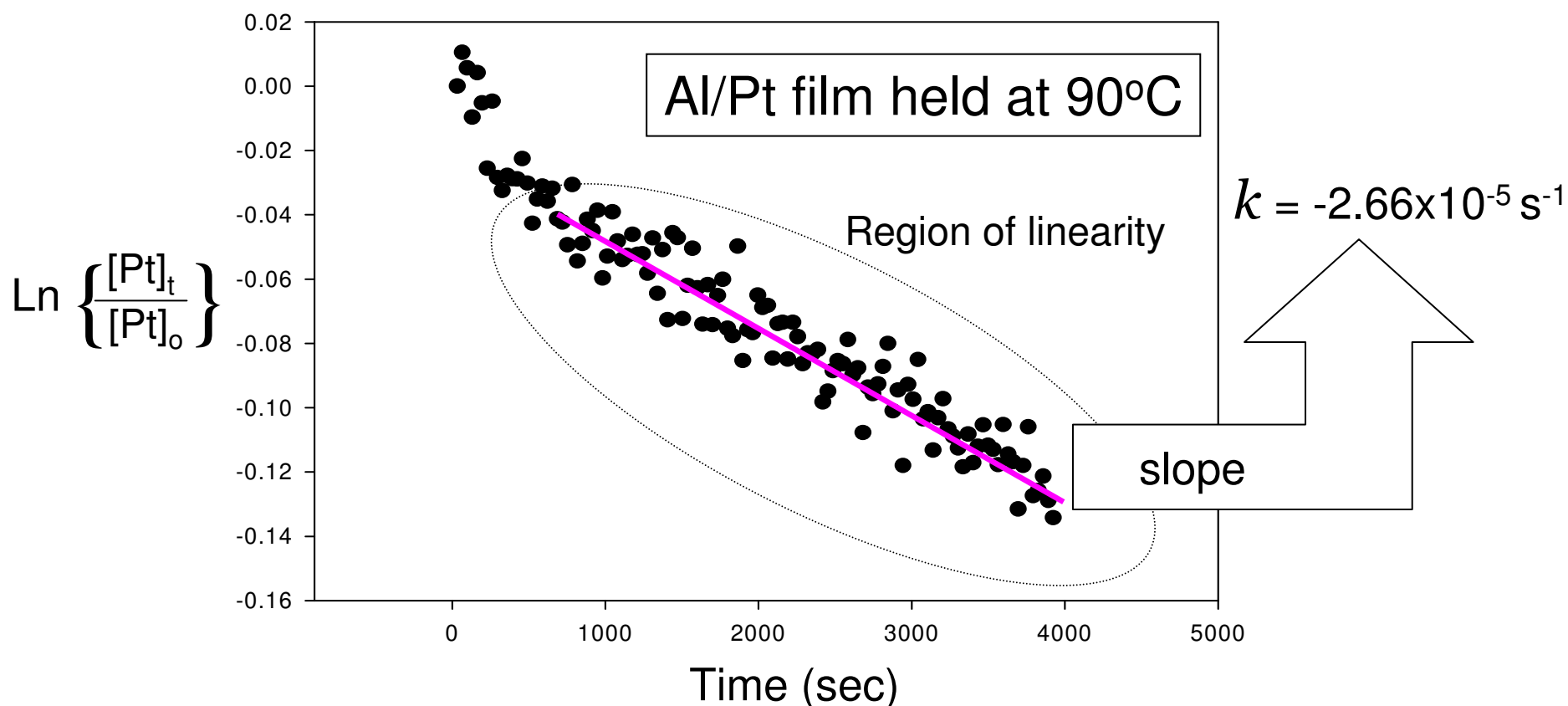


- Temperature calibrated via alumina thermal expansion
- Films heated 10°C/min to various hold temperatures
 - Vacuum ($\sim 10^{-2}$ Torr)
- Data collected using Hi-Star area detector
 - 120 frames @ 30 sec/frame
 - 1 hr total collection time/film
 - 1 mm incident beam snout
- Data integrated in GADDS
- Peak profile fitting performed using JADE 8.5

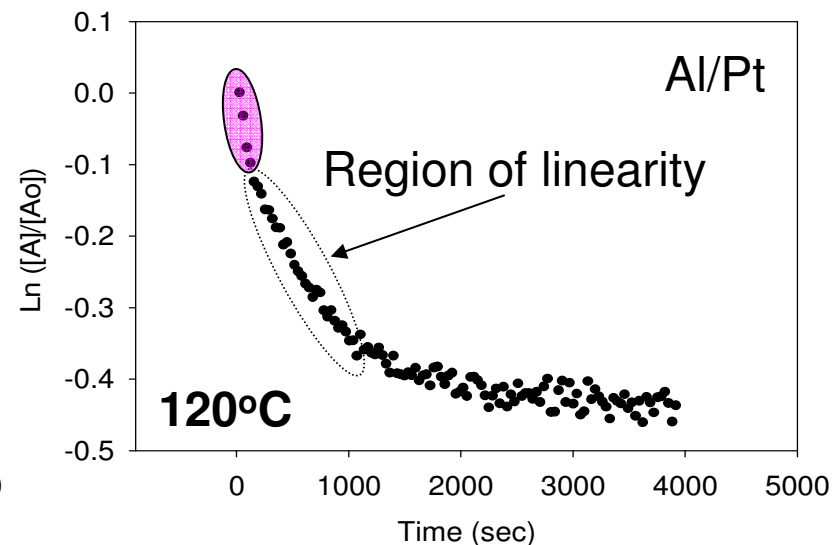
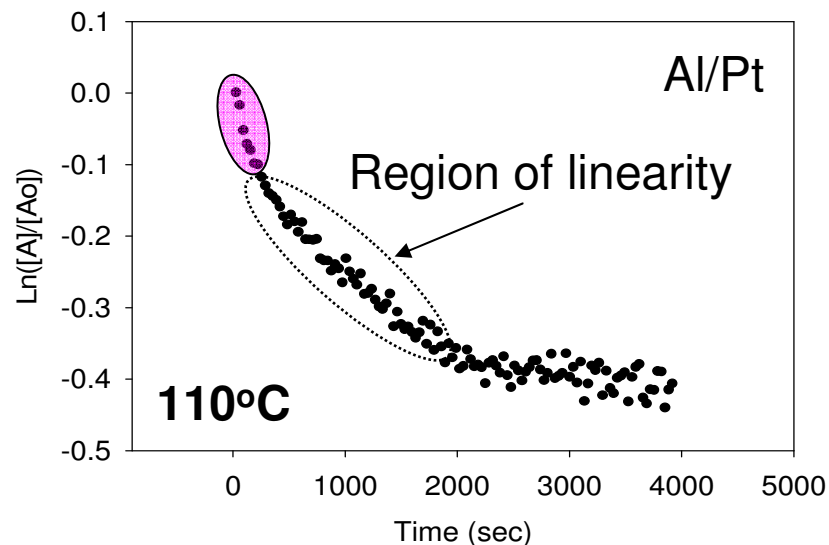
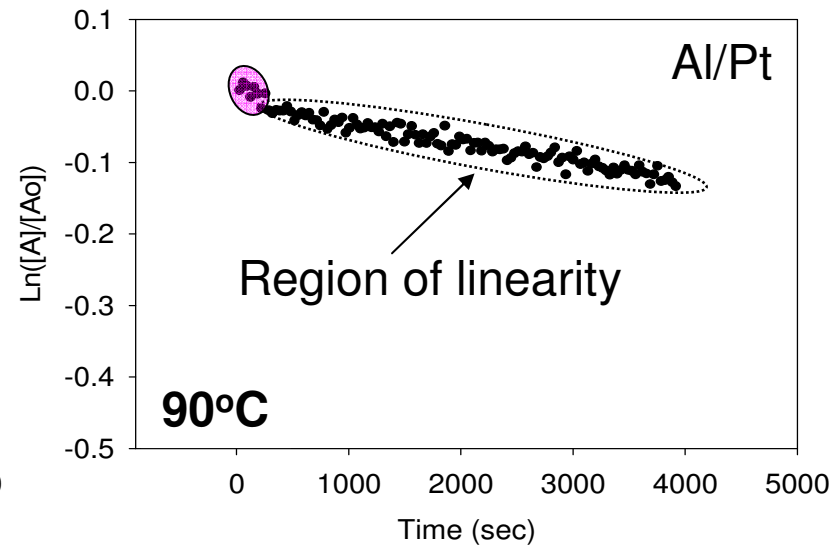
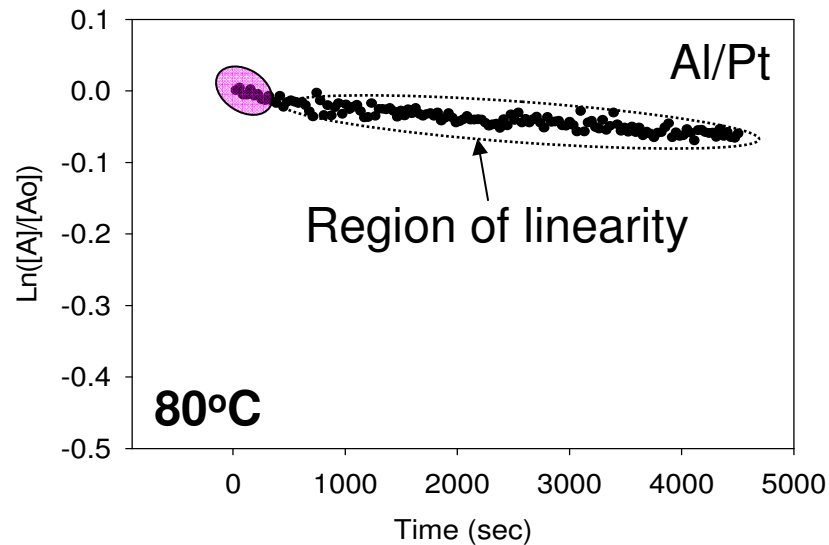


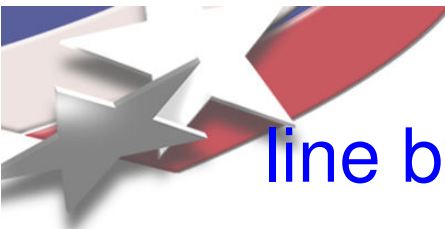
To generate a rate constant for a given (T)
we plot the natural log of concentration vs. time

We assume that the intensity of the Pt (111) is \propto to [Pt]

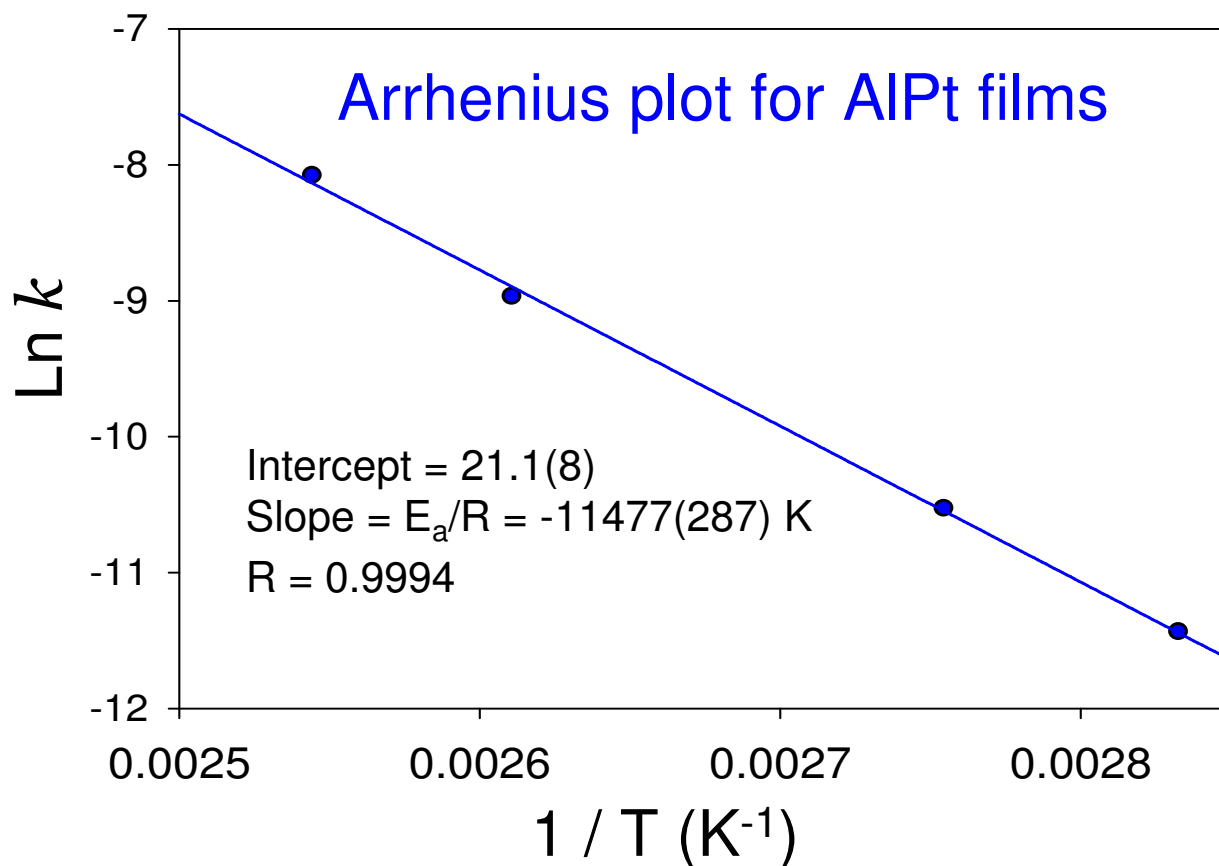


Increased reaction rate in first few minutes attributed to temperature overshoot of controller





Plot of $\ln(\text{rate constants})$ vs. $1/T$ generates line by which activation energy may be calculated



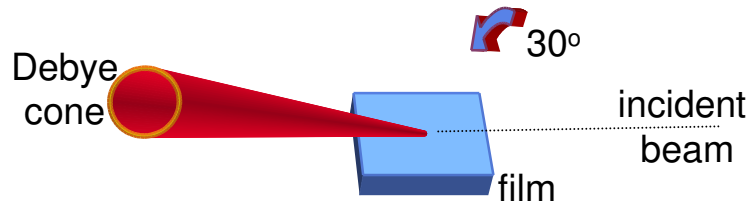
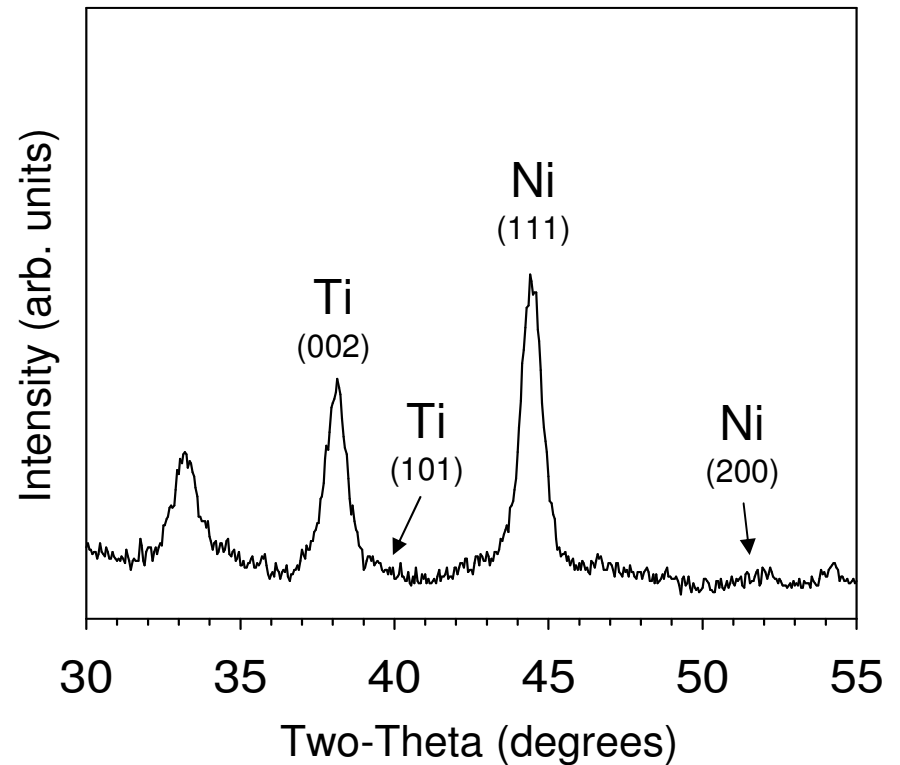
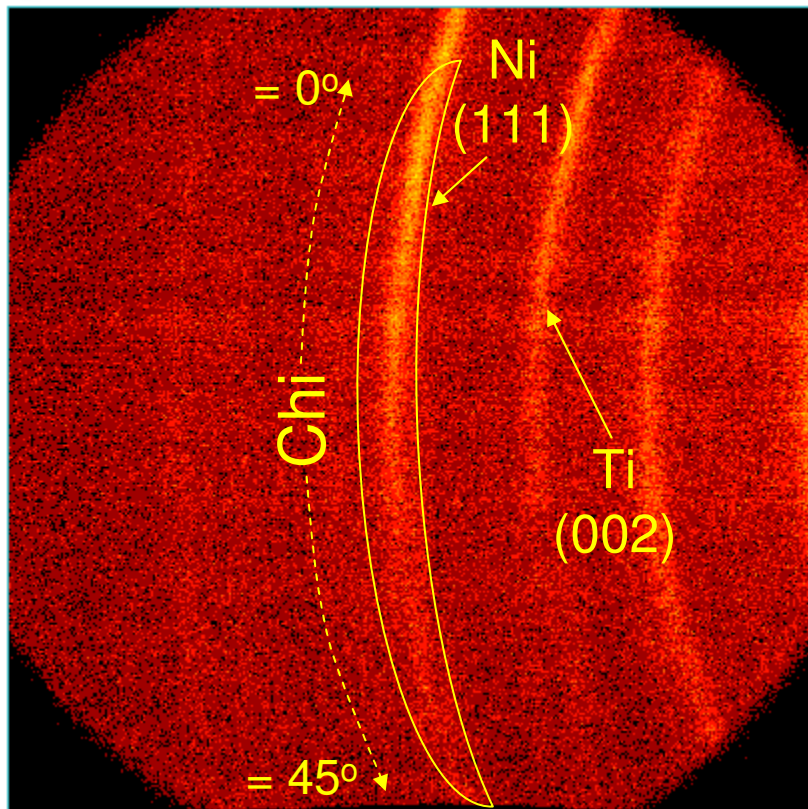
$$\text{AlPt } E_a = 1.1477 \times 10^4 \text{ (K)} * 8.314 \text{ (J K}^{-1}\text{mol}^{-1}) = 95.4 \pm 0.2 \text{ kJ/mol}$$



We have performed the same analysis for NiTi and CoAl Metal-Metal Multilayer films

- Lower scattering from lighter elements
- Needed to improve signal from film layers
- Bilayer thickness for Ni/Ti and Co/Al increased to 500 Å
- Increased total thickness for Ni/Ti and Co/Al to $\sim 1 \mu\text{m}$ (20 Bilayers)
- Films tended to be less oriented

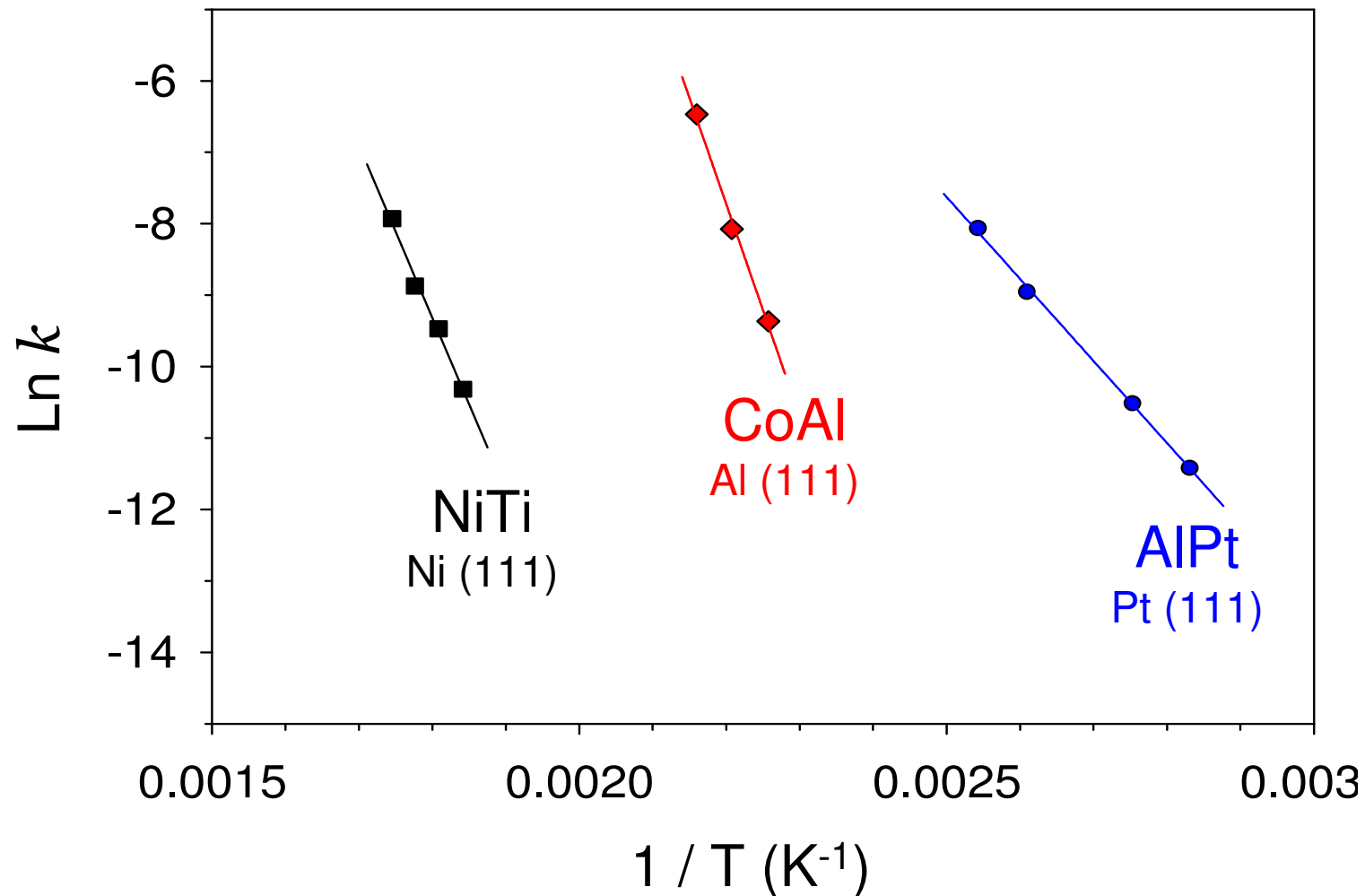
Ni/Ti shows out-of-plane texture of Ni (111) and Ti (002) but with larger variability in Chi angle



Film tilted 30° in Chi angle from normal to get at least **half** of intensity distributed along Chi



Ni/Ti and Co/Al films show higher E_a for intermixing as compared to Al/Pt





Analysis of reaction results for different film systems shows Al/Pt is most susceptible to the intermixing behavior

| Film | Bilayer Thickness (Å) | Number Bilayers | Total Thickness (nm) | Observed <i>hkl</i> | E _a (kJ/mol) | Rx Temp. range (°C) |
|-------|-----------------------|-----------------|-----------------------|---------------------|-------------------------|---------------------|
| Al/Pt | 400 | 5 | 0.20 | Pt (111) | 95.4(2) | 80-120 |
| Co/Al | 500 | 20 | 1.00 | Al (111) | 247(19) | 170-190 |
| Ni/Ti | 522 | 20 | 1.04 | Ni (111) | 201(13) | 270-300 |



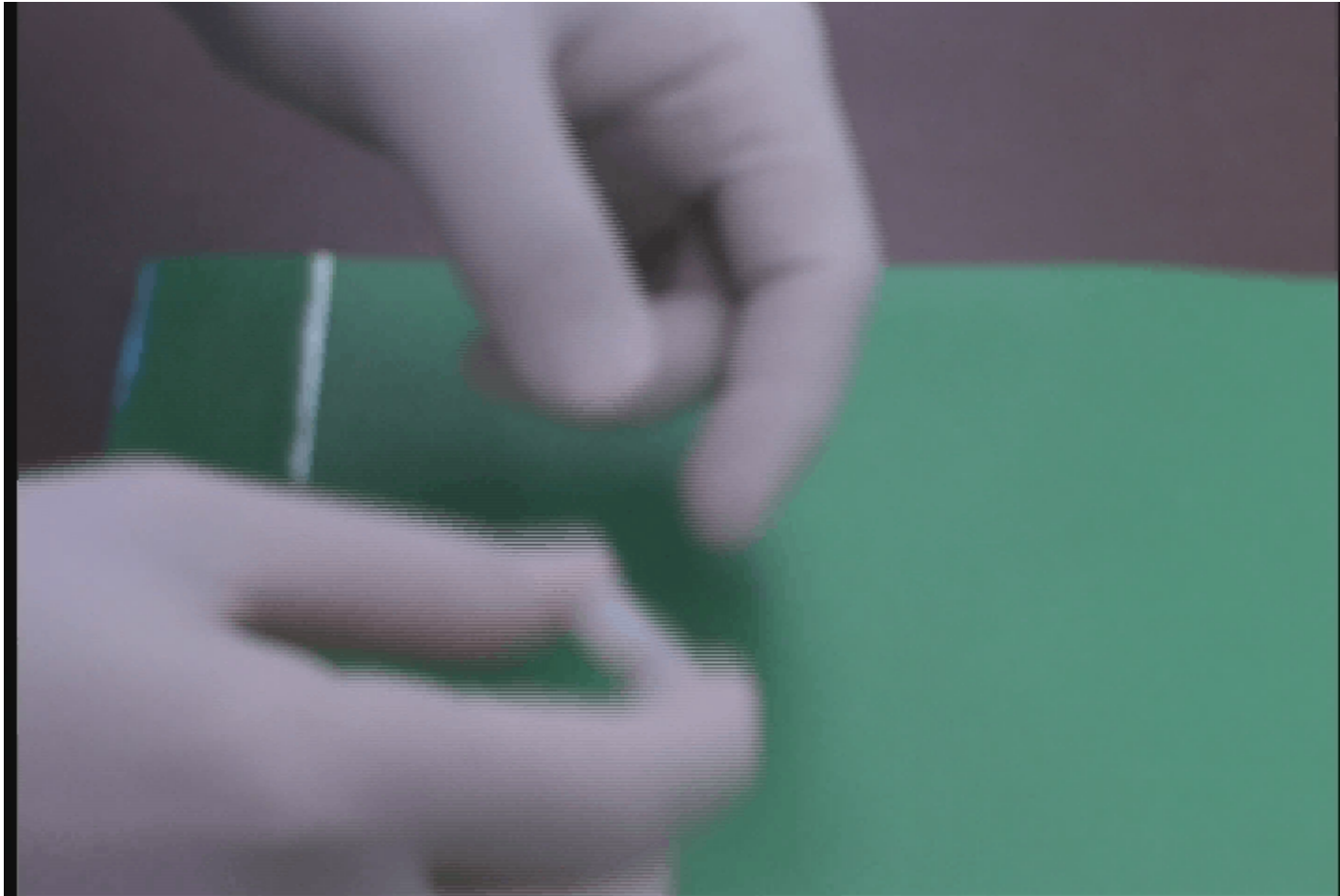
Conclusions

- Use of a 2D area detector facilitates collection of Rx kinetics data from textured films.
- Reactions can be monitored for both texture decay and intensity decay simultaneously.
- Al/Pt films show more susceptibility to intermixing reaction than Co/Al or Ni/Ti film systems.



Fun movie

Joining plastic via Ni/Al Exothermic Metal-Metal Multilayer films





Acknowledgments

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